US00D567125S

(12) **United States Design Patent**
Okabe et al.

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(54) **STRESS METER**

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(73) Assignee: **Nipro Corporation**, Osaka-Shi (JP)

(**) Term: **14 Years**

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(22) Filed: **Apr. 27, 2006**

(30) **Foreign Application Priority Data**

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(51) **LOC (8) Cl.** **10-04**
(52) **U.S. Cl.** **D10/81**; D10/78; D24/169
(58) **Field of Classification Search** D10/83, D10/78, 81; D24/224, 232, 169; 205/785.5, 205/787.5, 782; 204/415, 416, 403.2, 403.06, 204/409, 412, 435; 700/17, 431, 499, 866.3; 600/345, 587, 595, 300, 301; 345/824, 156, 345/158; 455/12.1, 86, 406; 422/50-58, 422/61-63, 67, 68.1, 80, 82.03; 435/7.21, 435/14, 22; 340/573.1, 573.3, 573.4
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D309,867 S	*	8/1990	Johnson	D10/81
D318,245 S	*	7/1991	Sierra et al.	D10/81
D418,134 S	*	12/1999	Crump	D24/169
D459,811 S	*	7/2002	Maus et al.	D24/169
7,183,069 B2	*	2/2007	Yamaguchi et al.	435/22

* cited by examiner

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(57) **CLAIM**

The ornamental design for a stress meter, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a stress meter;
FIG. **2** is a front view thereof;
FIG. **3** is a rear view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top view thereof; and,
FIG. **7** is a bottom view thereof.

1 Claim, 4 Drawing Sheets

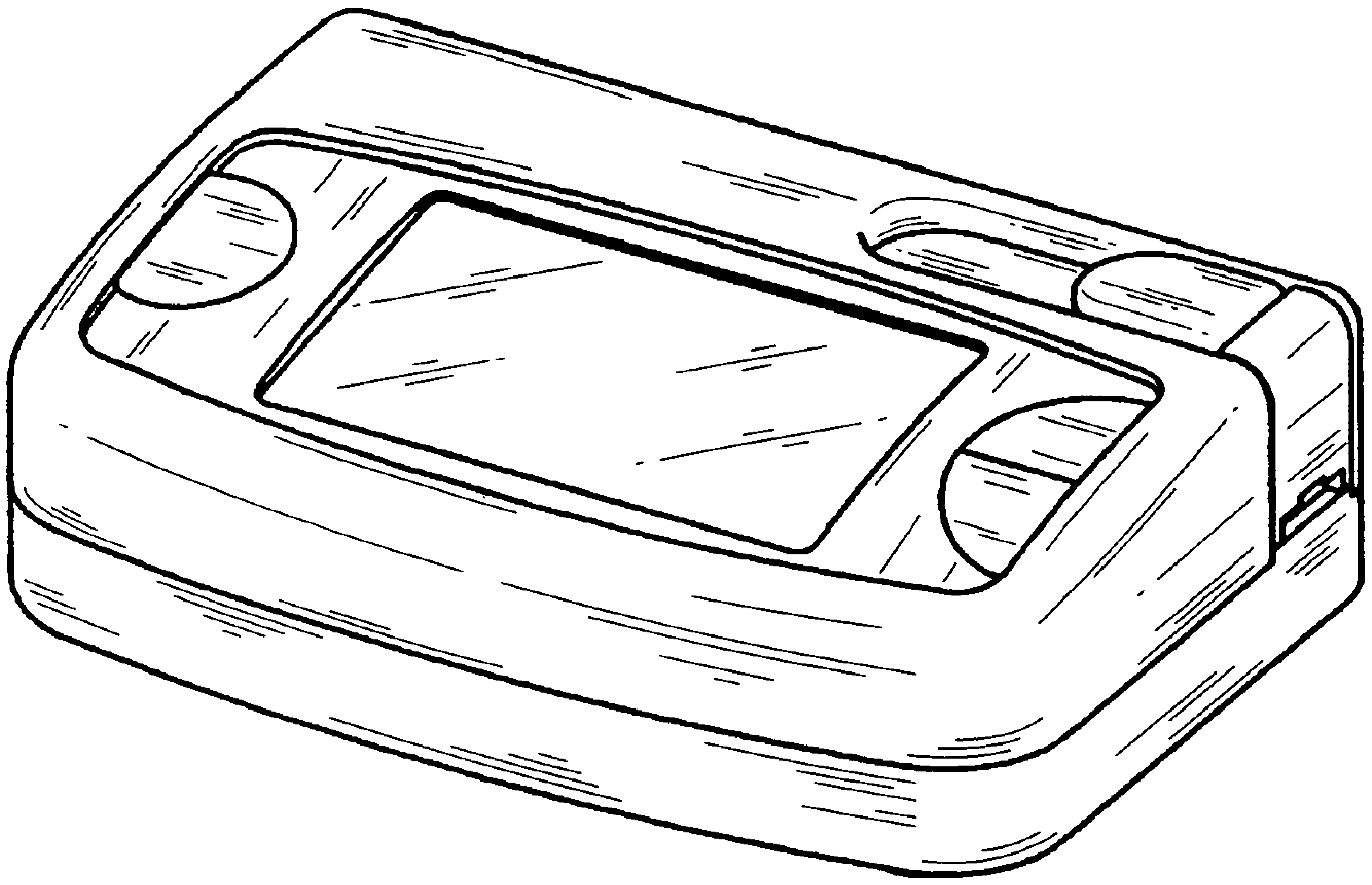

Fig.1

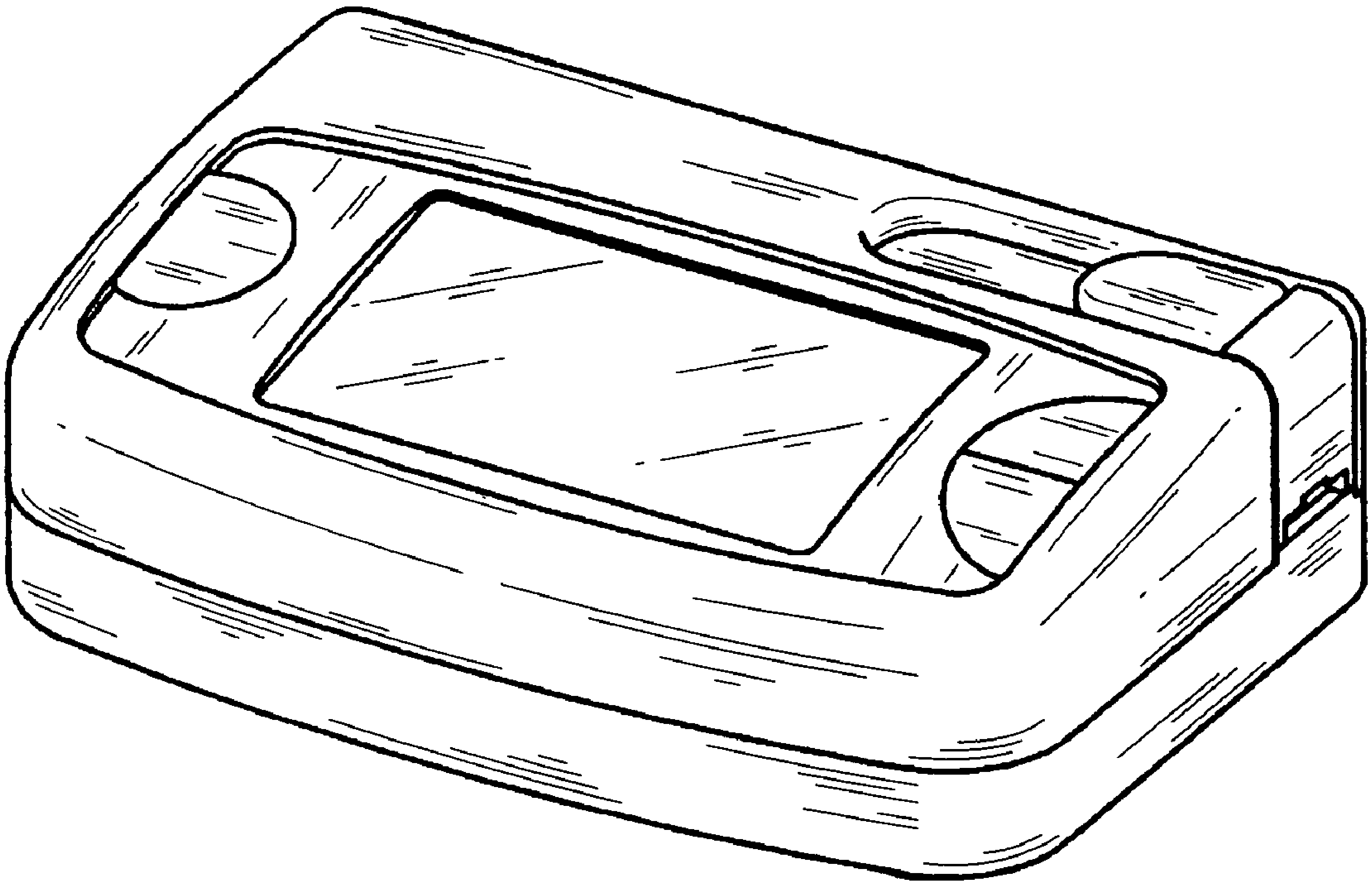

Fig.2

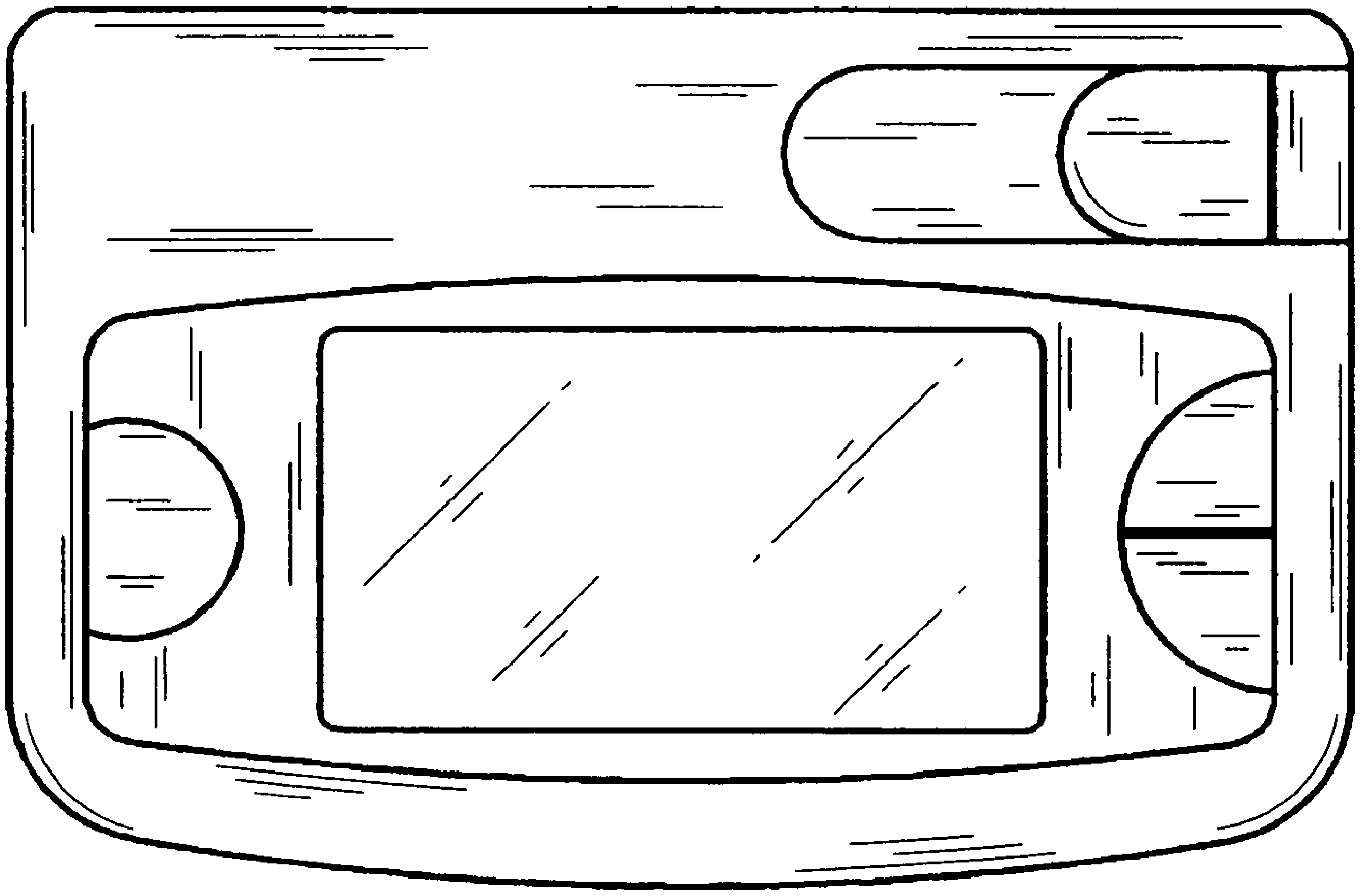

Fig.3

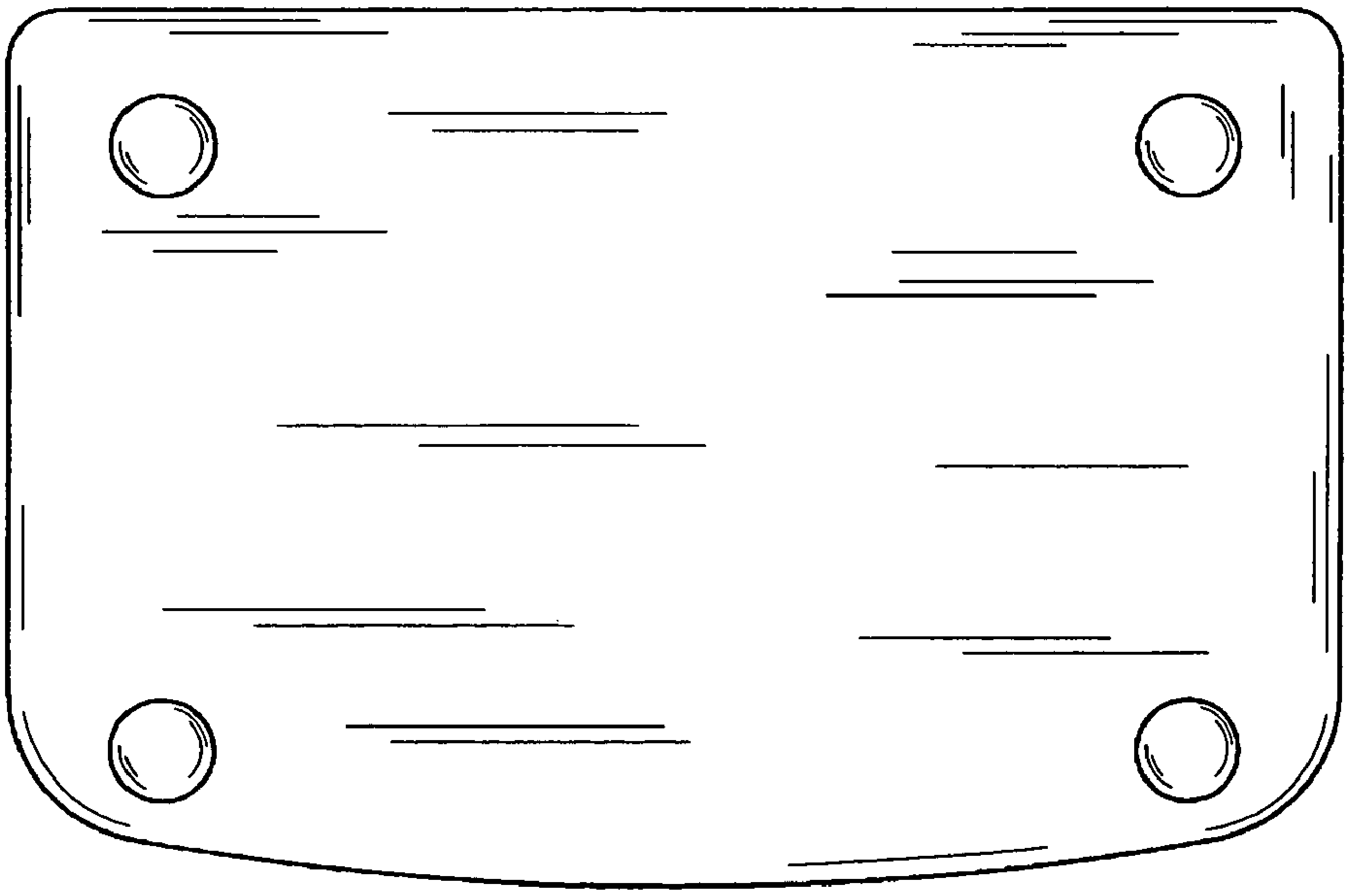

Fig.4

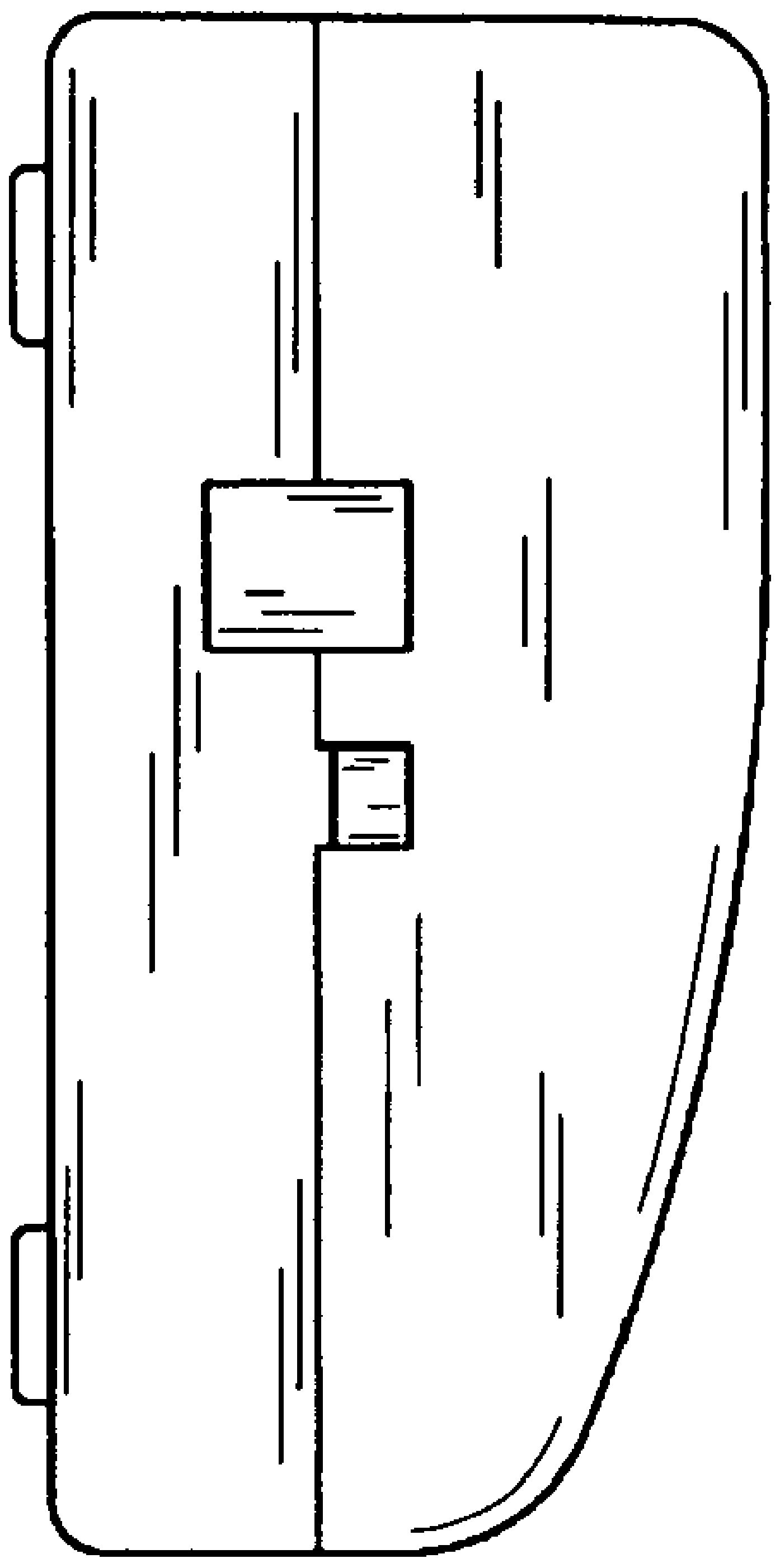

Fig.5

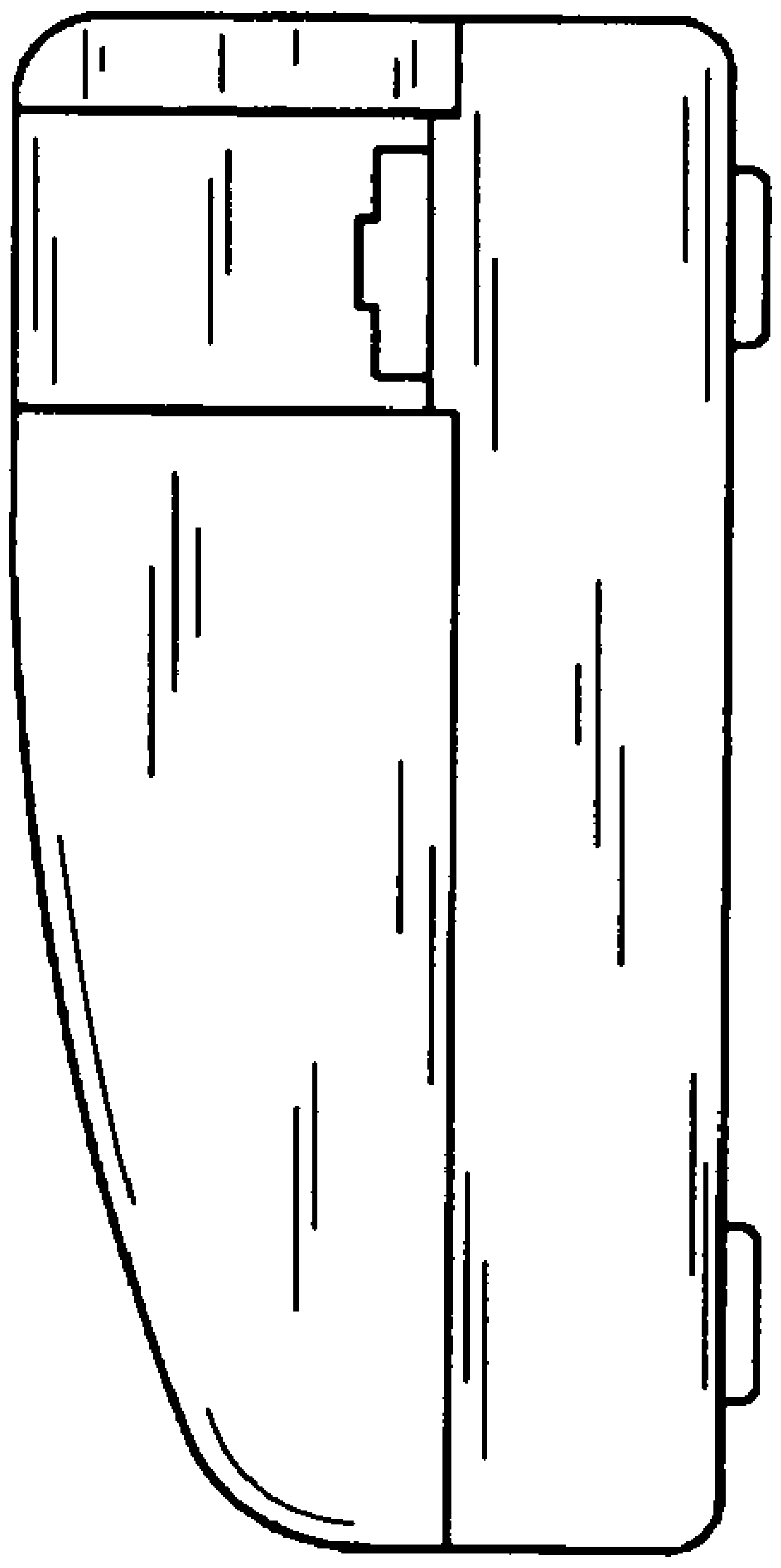

Fig.6

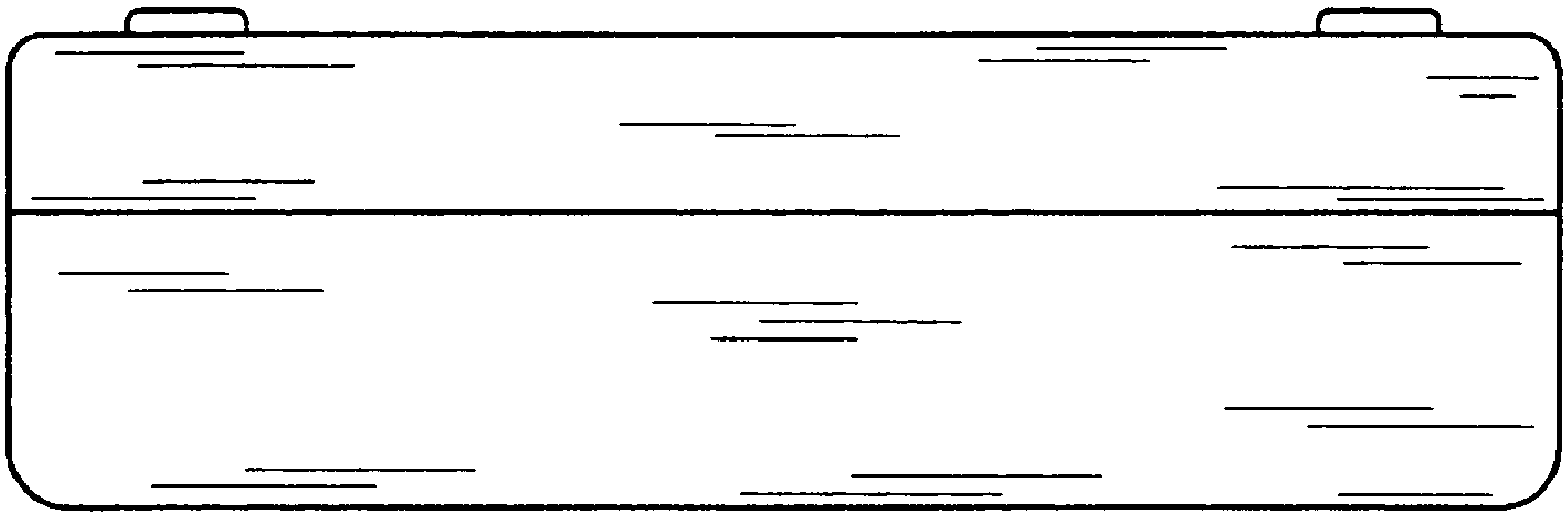

Fig.7